

Gj Yfcj bYcgYVbYHYca i b] UMYfl DHLEI DHZUnU&E: i b_VYg UgdyWZ UMYU
j a Ygb] U]dcj bY_UhWYf77 L'g]ghYa UI DH]b`bUdfUj ž_]gdfYYa U`c`lc`_UfWt
f758L'E8j chcbg_UjY ZY_j Yb bUfB HA: L'bUdfUj UZ_]gdfYYa U_UhWYI DH'E
GdYWZ UMYUnUdfYg_i yUb`Yg`UXbcgh

Universal Personal Telecommunication (UPT); UPT phase 2; Functional specification of the interface of a UPT Integrated Circuit Card (ICC) and Card Accepting Devices (CADs); UPT card accepting Dual Tone Multiple Frequency (DTMF) device; Conformance test specification

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UPT phase 2;
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